Active Edge and 3D Sensors



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Project Members

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Standard Planar



•Many Dangling Bonds

•Effective Short Between Surfaces

Active Edge Concept

Wrap Top Field Oxide Around Side



Active Edge Concept

Wrap Bottom Implant Around Side



Fabrication

Use Support Wafer

►No Sawing

Plasma Dice Instead

Dope and Grow Field Oxide on Edges

Otherwise same as Standard Planar



ALS X-ray microbeam signal on the IST and 2ND channels of a Active Edge planar detector • Current

Current
 Integration
 Mode

16 Strips
150 mm Pitch
100 mm thick



•Diffusion Paths 100 mm long

- •Still 80% of Signal at Edge
- •Low Trapping Probability
- •Long Life times in Bulk

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O Volts Bias





Wire Bonds

60-80
40-60
20-40



Sensitive up to Edge





2 µm Grid

Benefits for Crystallography

Direct absorption in silicon: Single X-photon sensitivity (Pseudo) counting detector: dynamic range??

active edges => large area can be covered with small sensors (yield!) and with near zero insensitive border areas

Quasi-continuous readout with no deadtime (continuous spindle rotation?)

Single pixel spatial response (~100µm typical 'pixel' size)



Courtesy of MBC Phil Matsumura



System Geometry



ASIC Design

- 1. 64 x 64 pixels, each 150 µm x 150 µm.
- 2. Readout pixels are only 144 μ m x 150 μ m, keeping the readout chip fully under the sensor.
- 3. Each pixel has an integrating amplifier.
- 4. 2 rows are read out together, using 128 lines.
- 5. Integration resumes after 1 µs.
- 6. Pulse heights are digitized in a Wilkinson ADC.
- 7. Readout moves to next two rows after an additional µs.
- Data is output to the computer from alternate buffers. The full sensor is readout every 64 μs.
- 9. Charge-shared signals can be recombined in the computer.
- 10. Small replaceable units for efficiency

PXTAL ASIC

8 by 64 Pixel Array, plus Full-Size 9th Test Column
128 ADCs



PXTAL Bumps

- Indium Bumps Deposited at Stanford
- Indium to Indium
- o 4 mm Bump Height
- Flip-chip Bonding Done at Stanford



150002 15KV X1.00K 30um

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Photon Counting



- Simultaneous Fit to All 8 Peaks
- Fit to Poisson Distribution Envelope



TOTEM

- LHC Experiment
- Roman Pots 220 m from CMS
- Close to Beam
- Active Edge is Critical for Physics





- 10 cm² Sensors
- 120 Sensors

TOTEM SENSOR BEHAVIOR



Entries Signal/noise dist top test 4 h10 Mean 18.51 n S/N

T4-4C at 60V

NICE IV CURVE
NO EXCESS EDGE CURRENT
NORMAL LANDAU

3D with Active Edges

- No Guard Rings
- No Dead Area at Edges
- Allows Seamless Tiling
- Edge is an Electrode
- Efficient Wafer Use
- 200 mm pitch
- 16 Strips
- 180 **nm** thick



3D Active Edge



- 1. NIMA 395 (1997) 328
- 2. IEEE Trans Nucl Sci 464 (1999) 1224
- 3. IEEE Trans Nucl Sci 482 (2001) 189
- 4. IEEE Trans Nucl Sci 485 (2001) 1629
- 5. IEEE Trans Nucl Sci 48 6 (2001) 2405
- 6. CERN Courier, Vol 43, Jan 2003, pp 23-26
- 7. NIMA 509 (2003)86-91



3D silicon detectors were proposed in 1995 by S. Parker, and active edges in 1997 by C. Kenney.

Combine traditional **VLSI** processing and **MEMS** (Micro Electro Mechanical Systems) technology.

Electrodes are processed inside the detector bulk instead of being implanted on the Wafer's surface.

The edge is an electrode! Dead volume at the Edge < 2 microns! Essential for -Large area coverage -Forward physics

AMERICIUM 14 KeV PEAK



3D Active Edge Scan



Sensitive to Within 2 mm of Edge!

Based on Full-Width at Half Maximun Drawn Strip Pitch = 200 mm Measured InterStrip Pitch = 199 +/- 2 mm



Measured Edge Strip Width = 200 +/- 2 mm

X5 test beam at CERN



• 3D

Active Edge

•180 μm Thick

16 Strips

• 100 GeV Muons

• 5 μm Telescope



Some results from the CERN X5 beam test (100 GeV muons)



Measured hit position in 3D sensor plane #3 vs. predicted position from beam telescope.

Fitted 3D sensor width = $3,203 \pm 4\mu m$. Drawn width = $3,195 \mu m$. Sensor efficiency = 98%. System efficiency less due to DAQ, triggering electronics.

3Dc Radiation hardness tests

Volume = 1.2 x 1.33 x 0.23 mm³ Inter-electrode spacing = 71 µm n-electrode readout n-type before irradiation



3D TIMING

- 0.25 micron amplifier and
- Response of sensor same as pulser
- 0.13 micron amplifier and 100 micron "diameter" hexagon/strip











- **ACTIVE EDGES for PHYSICS ACCEPTANCE**
- **3D for RADIATION DAMAGE**
- **PIXELS for MOMENTA RECONSTRUCTION**
- PIXELS for OCCUPANCY
 - 200 mm THICK
- 50 mm by 400 mm PIXELS
- **ROTATE SENSORS for X & Y**
- OFFSET PLANES s < 10 mm



	2E	3E	4E
Electrode Area (%)	4	6	8
Depletion Distance (microns)	100	70	50

Cell Design

- Single Sensor Yield > 50 %
- Breakdown Independent of Electrode Spacing
- Active Edges Robust against Breakdown





ATLAS UPGRADE

- ATLAS ASIC for FP420
- SENSORS FULLY COMPATIBLE with ATLAS ELECTRONICS
- 3D IS RAD HARD ENOUGH for B-LAYER



- BUMP 3D SENSORS and ATLAS ASICs
- CERN BEAM TEST in FALL
 2006



Tiling the Plane



PXTAL Movie

- o 12 keV Photons
- Detector Stage
 Scanned

